

# Radiation Hardended Ultra Low Dropout IR Adjustable Positive Linear Regulator +3.3V<sub>IN</sub> to

(5962F1023501K)
IRUH3301A1BK
IRUH3301A1BP
+3.3V<sub>IN</sub> to V<sub>ADJ</sub> @3.0A

#### **Product Summary**

Part Number	Dropout	I <sub>O</sub>	V <sub>IN</sub>	V <sub>OUT</sub>	
IRUH3301A1BK	0.4V	3.0A	3.3V	ADJ	
IRUH3301A1BP	0.40	3.0A	3.31	ADJ	



#### **Description**

The IRUH3301A1 is a space qualified, ultra low dropout linear regulator designed specifically for applications requiring high reliability, low noise and radiation hardness. The output voltage can be adjusted to a low 0.8V with a droput voltage of 400mV at the full rated current of 3.0 Amps.

#### **Features**

- Silicon On Insulator (SOI) CMOS Regulator IC, CMOS Latch-Up Immune, Inherently Rad Hard
- Total Dose Capability up to 300Krads(Si) (Condition A); Tested to 500Krad (Si)
- ELDRS up to 100Krad(Si) (Condition D)
- SEU Immune up to LET = 80 MeV\*cm<sup>2</sup>/mg
- Space Level Screened
- Fast Transient Response
- Timed Latch-Off Over-Current Protection
- Internal Thermal Protection
- Adjustable Output as low as 0.8V
- On/Off Control via Shutdown Pin, Power Sequencing Easily Implemented
- Isolated Hermetic MO-078AA Package Ensures Higher Reliability
- This part is also available in 8 Lead Flat pack Package as IRUH3301A1AK / IRUH3301A1AP

#### **Absolute Maximum Ratings**

Parameter	Symbol	Min.	Max.	Units	
Power Dissipation @ T <sub>C</sub> = 125°C	P <sub>D</sub>	-	25	W	
Maximum Output Current @ Maximum	I <sub>O</sub>		Con Fig. 4	_	
Power Dissipation with no Derating		-	See Fig 4	Α	
Non-Operating Input Voltage	V <sub>IN</sub>	-0.3	+8.0		
Operating Input Voltage	V <sub>IN</sub>	2.9	6.4		
Ground	GND	-0.3	0.3	V	
Shutdown Pin Voltage	V <sub>SHDN</sub>	-0.3	V <sub>IN</sub> + 0.3		
Output Pin Voltage	V <sub>OUT</sub>	-0.3	V <sub>IN</sub> + 0.3		
Operating Case Temperature Range	T <sub>O</sub>	-55	+140		
Storage Temperature Range	T <sub>S</sub>	-65	+150	۰,	
Maximmum Junction Temperature	TJ	-	+150	°C	
Lead Temperature (Soldering 10sec)	TL	-	+300	1	
Pass Transistor Thermal Resistance, Junction to Case	R <sub>THJC</sub>	-	1.0	°C/W	

## **Electrical Characteristics ①** Pre-Radiation $@T_C = 25^{\circ}C$ , $V_{IN} = 3.3V$ (Unless Otherwise Specified)

Parameter	Test Conditions	Symbol	Min.	Тур.	Max.	Units
	$2.97V \le V_{IN} \le 3.8V$ , $50mA \le I_{OUT} \le 3.0A$		0.788	0.800	0.812	
	$2.97V \le V_{IN} \le 3.8V$ , $50mA \le I_{OUT} \le 3.0A$ ,		0.776	0.000	0.824	
Reference Voltage	-55°C to +125°C	V <sub>OUT</sub>		0.800	0.824	V
(Measured @ ADJ Pin)	$2.97V \le V_{IN} \le 3.8V$ , $50mA \le I_{OUT} \le 3.0A$ ,		0.772	0.800	0.816	
	Post -Rad		0.772	0.000	0.010	
Dropout Voltage ①	$I_O = 3.0A$ , $V_{OUT} = 2.5V$ , -55°C to +125°C,	$V_{\mathrm{DROP}}$	_	_	0.4	V
Diopout Voltage ©	Post -Rad	V DROP		_	0.4	٧
Current Limit	Over-Current Latching, -55°C to +125°C,	l==	3.5	-	-	А
Current Limit	Post -Rad	ILATCH	3.5			
Over-Current Time-to-Latch	I <sub>O</sub> > I <sub>LATCH</sub>	t <sub>LATCH</sub>	-	10	1	ms
Maximum Shutdown Temp.@		T <sub>LATCH</sub>	125	140	•	°C
Ripple Rejection®	$F= 120Hz, I_O = 50mA, -55^{\circ}C \text{ to } +125^{\circ}C$	PSRR	65	ı	1	dB
	F= 120Hz, I <sub>O</sub> = 50mA, Post -Rad	PORR	40	-	-	
ADJ Pin Current ②	-55°C to +125°C	I <sub>ADJUST</sub>	-	1.6	-	mA
Minimum SHDN Pin "On"	I <sub>SOURCE</sub> = 200μA, -55°C to +125°C	V		_	0.8	V
Threshold Voltage	Post -Rad	V <sub>SHDN</sub>	-	•	0.8	V
Maximum SHDN Pin "Off"	I <sub>SOURCE</sub> = 200μA, -55°C to +125°C	V	1.2	-	ı	V
Threshold Voltage	Post -Rad	V <sub>SHDN</sub>	1.2			
Output Voltage at Shutdown	R <sub>LOAD</sub> = 36 Ohms, V <sub>SHDN</sub> = 3.3V	V <sub>OUT</sub>	-0.1	-	0.1	٧
Output Voltage at Shutdown	-55°C to +125°C, Post-Rad	VOUT				
SHDN Pin Leakage Current ②	$V_{SHDN} = 3.3V, -55^{\circ}C \text{ to } +125^{\circ}C, Post-Rad$	I <sub>SHDN</sub>	-10	-	10	μΑ
SHDN Pin Pull-Up Current ©	V <sub>SHDN</sub> = 0.4V		-98	-	-56	
	$V_{SHDN} = 0.4V, -55^{\circ}C \text{ to } +125^{\circ}C$	I <sub>SHDN</sub>	-140	-	-30	μΑ
	V <sub>SHDN</sub> = 0.4V, Post-Rad		-98	-	-56	
Power On Reset Threshold ②	Sweep V <sub>IN</sub> and Measure Output	V <sub>T-POR</sub>	-	1.7	1	V
Quiescent Current ②	No Load	I-	_	-	15	mA
Quiescent Current &	Full Load	ΙQ	-	-	90	

#### Notes:

① Connected as shown in Fig.1 and measured at the junction of V<sub>OUT</sub> and ADJ Pins.
 ② Under normal closed-loop operation. Guaranteed by design. Not tested in production.

#### **Radiation Performance Characteristics**

Test	Conditions	Min	Тур	Unit
	MIL-STD-883, Method 1019 (Condition A)			
Total Ionizing Dose (Gamma)	Operating Bias applied during exposure	300	500 ①	Krads (Si)
	Minimum Rated Load, Vin = 6.4V			
	MIL-STD-883, Method 1019 (Condition D)			
Total Ionizing Dose (Gamma)	(ELDRS) Operating Bias applied during	100	See ②	Krads (Si)
	exposure Minimum Rated Load, Vin = 6.4V			
Single Event effects	Heavy Ions (LET)			
SEU, SEL, SEGR, SEB	Operating Bias applied during exposure			MeV*cm <sup>2</sup> /mg
	under varying operating conditions			
Neutron Fluence	MIL-STD-883, Method 1017		1.0e <sup>11</sup>	Neutrons/cm <sup>2</sup>

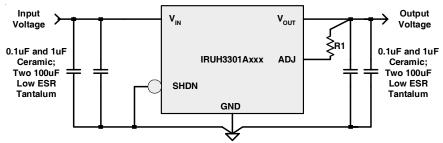
#### Notes:

- ① Tested to 500Krad (Si). ② See Fig. 5.

### **Space Level Screening Requirements**

TEST/INSPECTION	SCREENING LEVEL	MIL-STD-883
	SPACE	METHOD
Nondestructive Bond Pull	100%	2023
Internal Visual	100%	2017
Seal	100%	1014
Temperature Cycle	100%	1010
Constant Acceleration	100%	2001
Mechanical Shock	100%	2002
PIND	100%	2020
Pre Burn-In-Electrical	100%	
Burn-In	100%	1015
Final Electrical	100%	
Radiographic	100%	2012
External Visual	100%	2009

#### **Application Information**



**Fig. 1.** Typical Regulator Circuit; Note the SHDN Pin is hardwired in the "ON" position. The ADJ Pin is connected as noted in the "General Layout Rules" section.

#### **Setting the Output Voltage**

Choose R1 based upon the desired output voltage using the formula below.

$$R1 = \left(\frac{V_{OUT}}{0.800V} - 1\right) * 499\Omega$$

Table 1 shows the closest nominal 0.1% tolerance R1 value to provide a given output voltage.

Table 1- Values of R1 for a Given Output Voltage

V <sub>OUT</sub> (V)	0.9	1.0	1.2	1.5	1.8	2.0	2.5
Nearest R1 Value (0.1%), (Ohms)	61.9	124	249	437	619	750	1060

#### **Over-Current & Over-Temperature Protection**

The IRUH3301 series provides over-current protection by means of a timed latch function. Drive current to the internal PNP pass transistor is limited by an internal resistor (Rb in Fig. 3) between the base of the transistor and the control IC drive FET. If an over-current condition forces the voltage across this resistor to exceed 0.5V (nom), the latch feature will be triggered. The time-to-latch ( $t_{LATCH}$ ) is nominally 10ms. If the over-current condition exists for less than  $t_{LATCH}$ , the latch will not be set. If the latch is set the drive current to the PNP pass transistor will be disabled. The latch will remain set until one of the following actions occur:

- 1. The SHDN Pin voltage is brought above 1.2V and then lowered below 0.8V.
- 2. The V<sub>IN</sub> Pin voltage is lowered below 1.7V.

If the junction temperature of the regulator IC exceeds 140°C nominal, the thermal shutdown circuit will set the internal latch and disable the drive current to the PNP pass transistor as described above. After the junction temperature falls below a nominal 125°C, the latch can be reset using either of the actions described above.

#### **Under-Voltage Lock-Out**

The under-voltage lock-out (UVLO) function prevents operation when  $V_{IN}$  is less than 1.7V (nominal). There is a nominal 100mV hysteresis about this point.

#### Input Voltage Range

The device functions fully when  $V_{IN}$  is greater than 2.9V. It enters into under-voltage lock-out at  $V_{IN}$  < 1.7V (nominal). When 1.7V (nominal) <  $V_{IN}$  < 2.9V,  $V_{OUT}$  will track  $V_{IN}$  and overshoot may occur. A larger output capacitor should be used to slow down the  $V_{OUT}$  rise rate for slow  $V_{IN}$  ramp applications.

#### Shutdown (SHDN)

The regulator can be shutdown by applying a voltage of >1.2V to the SHDN Pin. The regulator will restart when the SHDN Pin is pulled below the shutdown threshold of 0.8V. If the remote shutdown feature is not required, the SHDN Pin should be connected to GND.

#### **Input Capacitance**

Input bypass capacitors: Two  $(0.1\mu F$  and  $1\mu F)$  ceramics and two  $100\mu F$  low ESR tantalums (AVX TPS or equivalent), placed very close to the  $V_{IN}$  Pin are required for proper operation. When the input voltage supply capacitance is more than 4 inches from the device, additional input capacitance is recommended. Larger input capacitor values will improve ripple rejection further improving the integrity of the output voltage.

#### **Output Capacitance**

Output bypass capacitors: Two  $(0.1\mu F$  and  $1\mu F)$  ceramics and two  $100\mu F$  low ESR tantalums (AVX TPS or equivalent) are required for loop stability. Faster transient performance can be achieved with multiple additional  $1\mu F$  ceramic capacitors. Ceramic capacitors greater than  $1\mu F$  in value are not recommended as they can cause stability issues.

Tantalum capacitor values larger than the suggested value are recommended to improve the transient response under large load current changes. The upper capacitance value limit is governed by the delayed over-current latch function of the regulator and can be as much as 10,000µF without causing the device to latch-off during start-up.

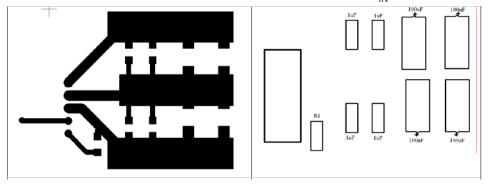
#### **General Layout Rules**

Low impedance connections between the regulator output and load are essential. Solid power and ground planes are highly recommended. In those cases where the board impedances are not kept very small, oscillations can occur due to the effect of parasitic series resistance and inductance on loop bandwidth and phase margin.

R1 must be directly conected to the  $V_{\text{OUT}}$  Pin using as short a trace as possible with the connection inside the first bypass capacitor (see Fig. 2a). The trace from ADJ Pin to R1 should be as short as possible.

Connect ceramic output capacitors directly across the  $V_{OUT}$  and GND Pins with as wide a trace as design rules allow (see Fig. 2a). Avoid the use of vias for these capacitors and avoid loops. Fig.2 shows the ceramic capacitors tied directly to the regulator output.

The input capacitors should be connected as close a possible to the  $V_{\text{\tiny INI}}$  Pin.



**Fig. 2a.** Layer 1 conductor.

Ground plane below layer 1 www.irf.com

Fig. 2b. Layer 1 silkscreen

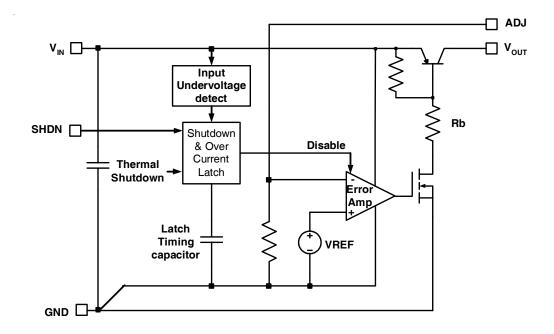
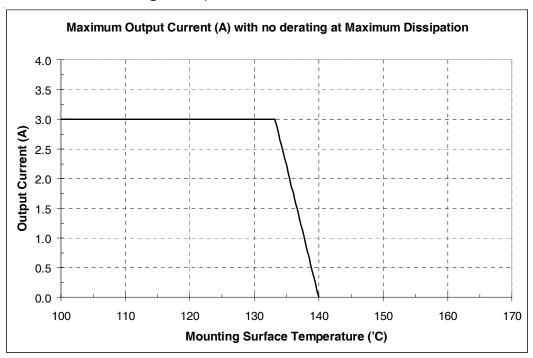


Fig. 3. Simplified Schematic Circuit



**Fig. 4.** Maximum Output Current versus Mounting Surface Temperature with no Derating at Maximum Dissipation

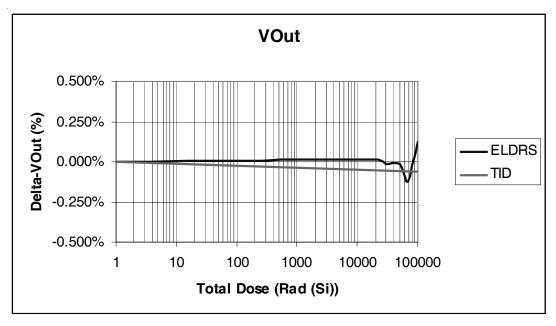
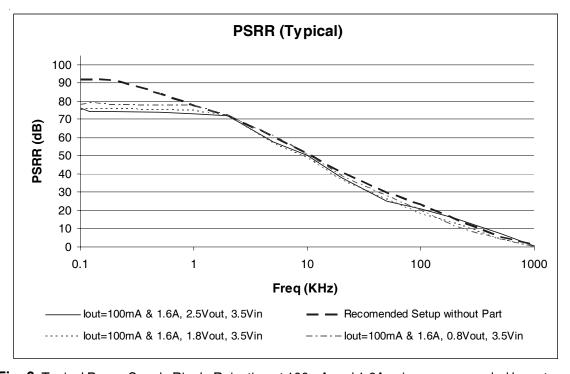


Fig. 5. Change in Output Voltage vs. Total Ionizing Dose Radiation Exposure at Both High and Low Dose Rates



**Fig. 6.** Typical Power Supply Ripple Rejection at 100mA and 1.6A using recommended layout and capacitors. Results above 10KHz are influenced by testing setup and layout.

Fig 7. Case Outline and Dimensions - MO-078AA (Lead Form Down)

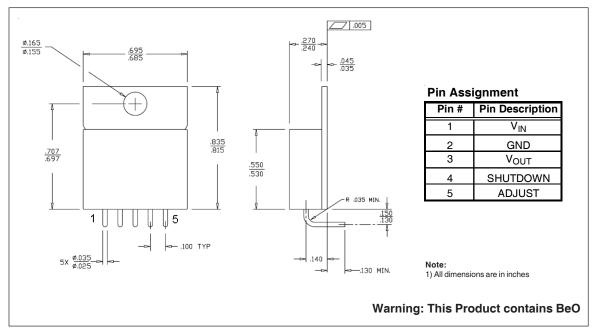


Fig 8. Case Outline and Dimensions - MO-078AA (Lead Form Up)

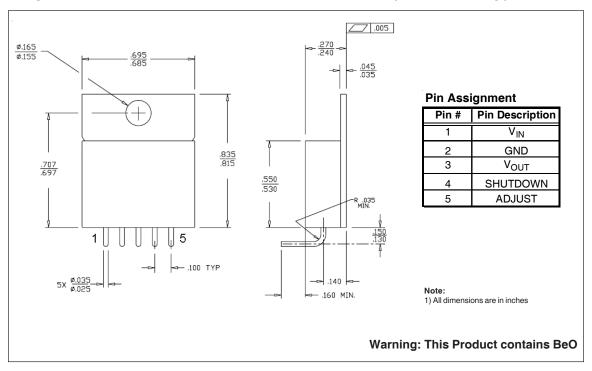
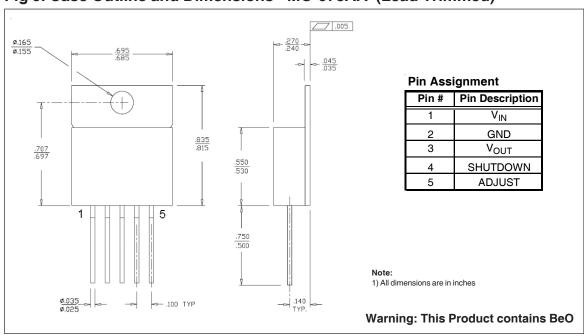
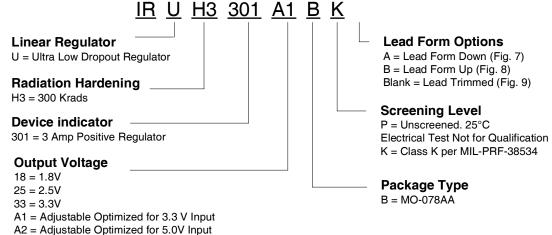


Fig 9. Case Outline and Dimensions - MO-078AA (Lead Trimmed)



# Part Numbering Nomenclature





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